

Preliminary

SIDC03D120F6

Fast switching diode chip in EMCON-Technology

FEATURES:

- 1200V EMCON technology 120 µm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

• EUPEC power modules and discrete devices



Applications:

• SMPS, resonant applications, drives

| Chip Type | V _R | I _F | Die Size | Package | Ordering Code |
|--------------|----------------|----------------|-----------------------------|--------------|-----------------------|
| SIDC03D120F6 | 1200V | 2A | 1.75 x 1.85 mm ² | sawn on foil | Q67050-A4168- A001 |

MECHANICAL PARAMETER:

| MECHANICAL FARAMETER. | | | | | |
|---------------------------------|---|-----------------|--|--|--|
| Raster size | 1.75 x 1.85 | | | | |
| Area total / active | 3.24 / 1.32 | mm ² | | | |
| Anode pad size | 1.03 x 1.13 | | | | |
| Thickness | 120 | μm | | | |
| Wafer size | 150 | mm | | | |
| Flat position | 180 | deg | | | |
| Max. possible chips per wafer | 4759 pcs | | | | |
| Passivation frontside | Photoimide | | | | |
| Anode metallisation | 3200 nm AlSiCu | | | | |
| Cathode metallisation | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding | | | | |
| Die bond | electrically conductive glue or solder | | | | |
| Wire bond | Al, ≤500µm | | | | |
| Reject Ink Dot Size | Ø 0.65mm ; max 1.2mm | | | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | | | |



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Maximum Ratings

| Parameter | Symbol | Condition | Value | Unit |
|--|---|-----------|---------|------|
| Repetitive peak reverse voltage | V _{RRM} | | 1200 | V |
| Continuous forward current limited by T _{jmax} | / _F | | 2 | |
| Single pulse forward current (depending on wire bond configuration) | I_{FSM} $t_P = 10 \text{ ms sinusoidal}$ | | tbd | А |
| Maximum repetitive forward current limited by T _{jmax} | I _{FRM} | | 4 | |
| Operating junction and storage temperature | T_{j} , T_{stg} | | -55+150 | °C |

Static Electrical Characteristics (tested on chip), T_j =25 °C, unless otherwise specified

| Parameter | Symbol | Cond | Value | | | Unit | |
|------------------------------------|-----------------|-----------------------|-------------------------------------|------|------|------|----|
| Falameter | Symbol | Conditions | | min. | Тур. | max. | |
| Reverse leakage current | I _R | V _R =1200V | <i>T_j</i> =25 ° <i>C</i> | | | 27 | μA |
| Cathode-Anode breakdown Voltage | V _{Br} | I _R =0.5mA | <i>T_j</i> =25°C | 1200 | | | V |
| Forward voltage drop | V _F | I _F =2A | <i>T_j</i> =25°C | | 2.1 | | V |

Dynamic Electrical Characteristics, at $T_j = 25$ °C, unless otherwise specified, tested at component

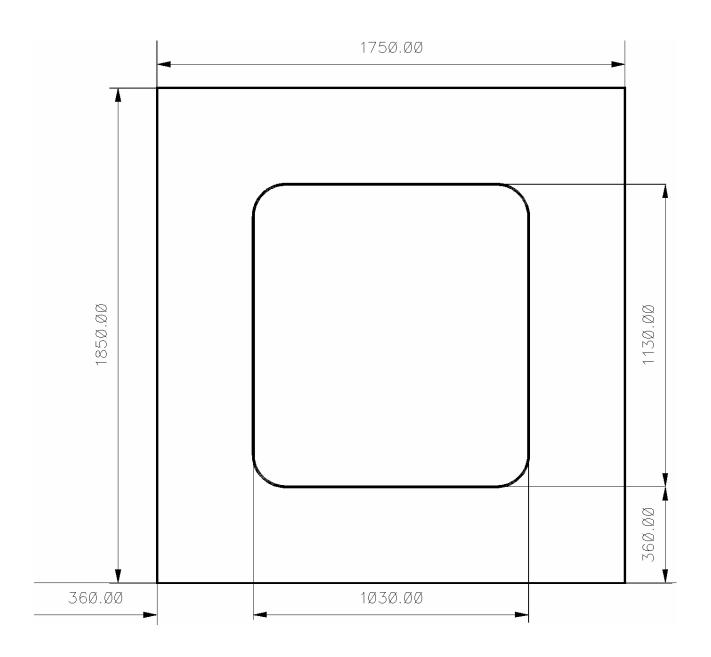
| Parameter | Symbol | Conditions | | | Value | | Unit |
|------------------------------|-----------------------|---|-------------------------------------|------|-------|------|------|
| | Symbol | | | min. | Тур. | max. | |
| Reverse recovery time | t _{rr1} | I _F =2A | $T_j = 25 °C$ | | tbd | | |
| | t _{rr2} | di/dt=A/ m s V _R =600V | $T_j = 150 ^{\circ}C$ | | | | ns |
| Peak recovery current | I _{RRM1} | I _F =2A | $T_j = 25 °C$ | | tbd | | А |
| | I _{RRM2} | di/dt = A/ms $V_R = 600V$ | $T_j = 150 ^{\circ}C$ | | | | ^ |
| Reverse recovery charge | Q _{rr1} | IF=2A | <i>T_j</i> =25 ° <i>C</i> | | tbd | | nC |
| | Q _{rr2} | di/dt = A/ms $V_R = 600V$ | <i>T_j</i> =150°C | | | | |
| Peak rate of fall of reverse | di _{rr1} /dt | I _F =2A | <i>T</i> _j =25°C | | tbd | | A (|
| recovery current | di _{rr2} /dt | di/dt = A/ms $V_R = 600V$ | <i>T_j</i> =150°C | | | | A/μs |
| Softness | S1 | $I_F=2A$ di/dt=A/ms | <i>T_j</i> =25 ° <i>C</i> | | tbd | | 1 |
| | S2 | $V_R = 600V$ | <i>T_j</i> =150°C | | | | |



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CHIP DRAWING:





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FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the | INFINEON TECHNOLOGIES / | tbd |
|------------------------------------|-------------------------|-----|
| device data sheet | EUPEC | lbu |

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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